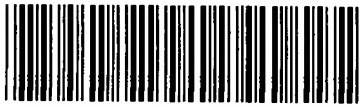


<b>Search Notes</b>  	<b>Application/Control No.</b>  10786164	<b>Applicant(s)/Patent Under Reexamination</b>  BEAN ET AL.
	<b>Examiner</b>  Chin-Shue, Alvin C	<b>Art Unit</b>  3634

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
182	18	4/27/07	acs

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>